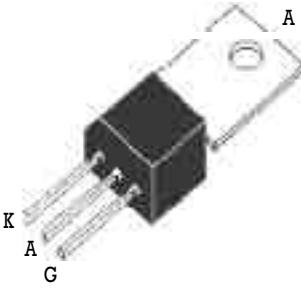
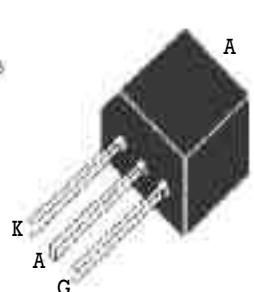


SENSITIVE GATE SCR

TO202-1 (E) 	TO202-3 (F) 	<p>On-State Current Gate Trigger Current 8 Amp < 200 μA</p> <p>Off-State Voltage 200 V ÷ 600 V</p> <p>These series of Silicon Controlled Rectifier use a high performance PNPN technology.</p> <p>These parts are intended for general purpose applications where high gate sensitivity is required.</p>
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Absolute Maximum Ratings, according to IEC publication No. 134

SYMBOL	PARAMETER	CONDITIONS	Min.	Max.	Unit
$I_{T(RMS)}$	On-state Current	180° Conduction Angle, $T_c = 110^\circ C$		8	A
$I_{T(AV)}$	Average On-state Current	Half Cycle, $\alpha = 180^\circ$, $T_c = 110^\circ C$		5	A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 60 Hz		73	A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 50 Hz		70	A
I^2t	Fusing Current	$t_p = 10ms$, Half Cycle		24.5	A^2s
V_{GRM}	Peak Reverse Gate Voltage	$I_{GR} = 10 \mu A$		8	V
I_{GM}	Peak Gate Current	20 μs max.		4	A
P_{GM}	Peak Gate Dissipation	20 μs max.		5	W
$P_{G(AV)}$	Gate Dissipation	20ms max.		1	W
T_j	Operating Temperature		-40	+125	$^\circ C$
T_{stg}	Storage Temperature		-40	+150	$^\circ C$
T_{sld}	Soldering Temperature	10s max.		260	$^\circ C$

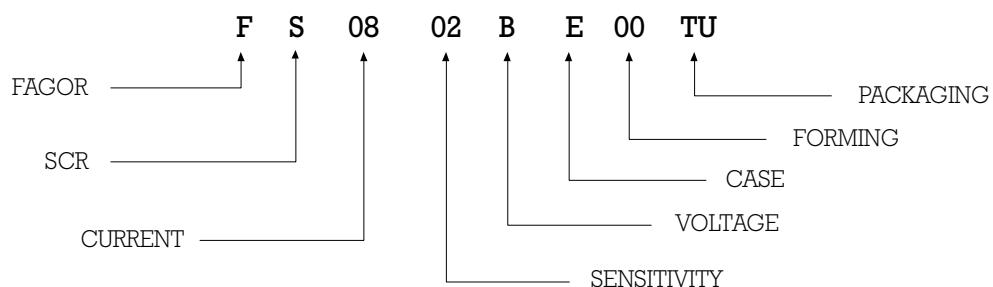
SYMBOL	PARAMETER	CONDITIONS	VOLTAGE			Unit
			B	D	M	
V_{DRM} V_{RRM}	Repetitive Peak Off State Voltage	$R_{GK} = 1 K$	200	400	600	V

SENSITIVE GATE SCR

Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS	SENSITIVITY		Unit
			02		
I_{GT}	Gate Trigger Current	$V_D = 12 \text{ V}_{DC}, R_L = 140 \Omega, T_j = 25^\circ\text{C}$	MIN MAX	200	μA
I_{DRM} / I_{RRM}	Off-State Leakage Current	$V_D = V_{DRM}, R_{GK} = 220 \Omega, T_j = 125^\circ\text{C}$ $V_R = V_{RRM}, T_j = 25^\circ\text{C}$	MAX MAX	1 5	mA μA
V_{TM}	On-state Voltage	at $I_T = 16 \text{ Amp}, t_p = 380 \mu\text{s}, T_j = 25^\circ\text{C}$	MAX	1.6	V
V_{GT}	Gate Trigger Voltage	$V_D = 12 \text{ V}_{DC}, R_L = 140 \Omega, T_j = 25^\circ\text{C}$	MAX	0.8	V
V_{GD}	Gate Non Trigger Voltage	$V_D = V_{DRM}, R_L = 3.3\text{K}, R_{GK} = 220 \Omega, T_j = 125^\circ\text{C}$	MIN	0.1	V
I_H	Holding Current	$I_T = 50 \text{ mA}, R_{GK} = 1\text{K}, T_j = 25^\circ\text{C}$	MAX	5	mA
I_L	Latching Current	$I_G = 1 \text{ mA}, R_{GK} = 1\text{K}$	MAX	6	mA
dv/dt	Critical Rate of Voltage Rise	$V_D = 0.67 \times V_{DRM}, R_{GK} = 220 \Omega, T_j = 125^\circ\text{C}$	MIN	5	$\text{V}/\mu\text{s}$
di/dt	Critical Rate of Current Rise	$I_G = 2 \times I_{GT}, t_p = 100 \text{ ns}, T_j = 125^\circ\text{C}$	MIN	50	$\text{A}/\mu\text{s}$
$R_{th(j-c)}$	Thermal Resistance Junction-Case for DC			20	$^\circ\text{C}/\text{W}$
$R_{th(j-a)}$	Thermal Resistance Junction-Amb for DC			100	$^\circ\text{C}/\text{W}$
V_{t0}	Threshold Voltage	$T_j = 125^\circ\text{C}$	MAX	0.85	V
R_d	Dynamic resistance	$T_j = 125^\circ\text{C}$	MAX	46	m

PART NUMBER INFORMATION



SENSITIVE GATE SCR

Fig. 1: Maximum average power dissipation versus average on-state current.

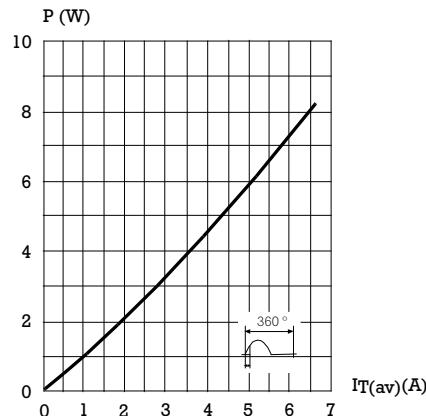


Fig. 2: Average and D.C. on-state current versus case temperature.

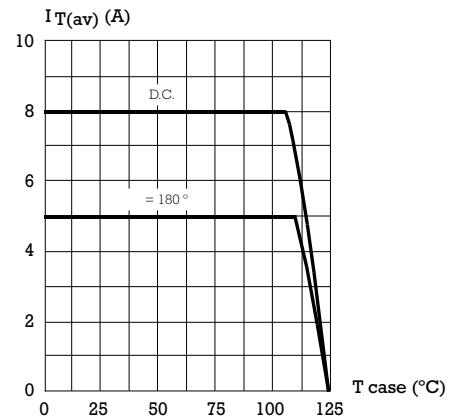


Fig. 3: Relative variation of thermal impedance junction to case versus pulse duration.

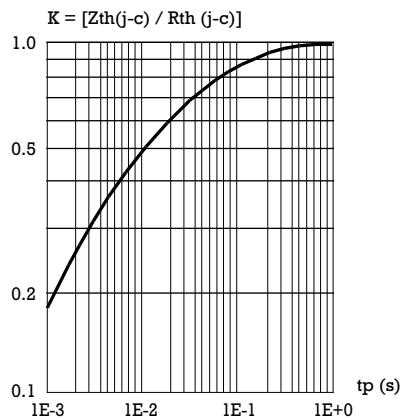


Fig. 5: Non repetitive surge peak on-state current versus number of cycles.

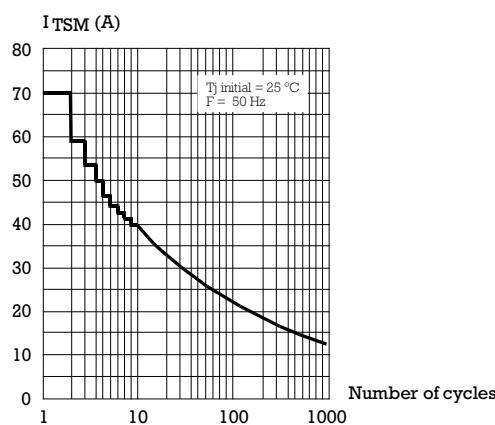


Fig. 4: Relative variation of gate trigger current, holding and latching current versus junction temperature.

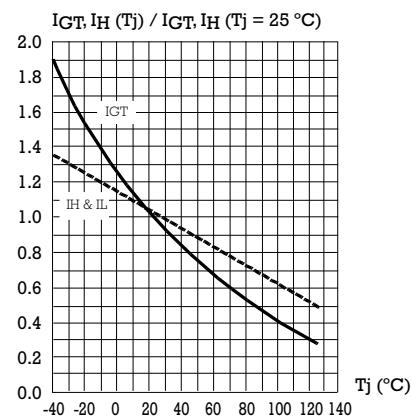
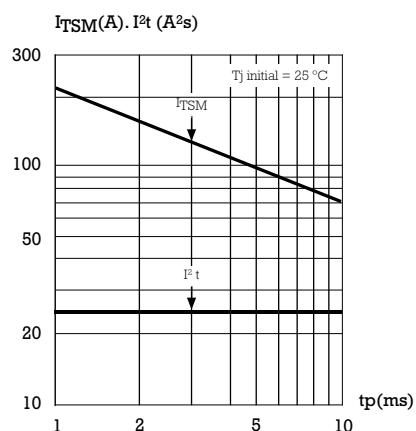
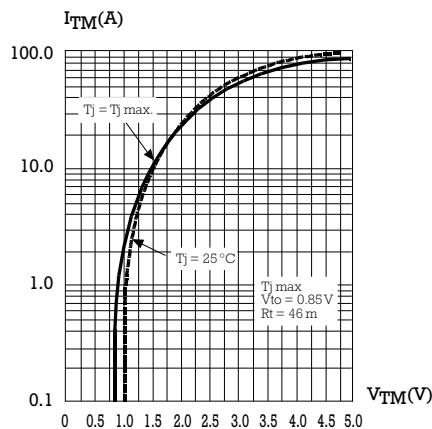


Fig. 6: Non repetitive surge peak on-state current for a sinusoidal pulse with width: tp < 10 ms, and corresponding value of I²t.



SENSITIVE GATE SCR

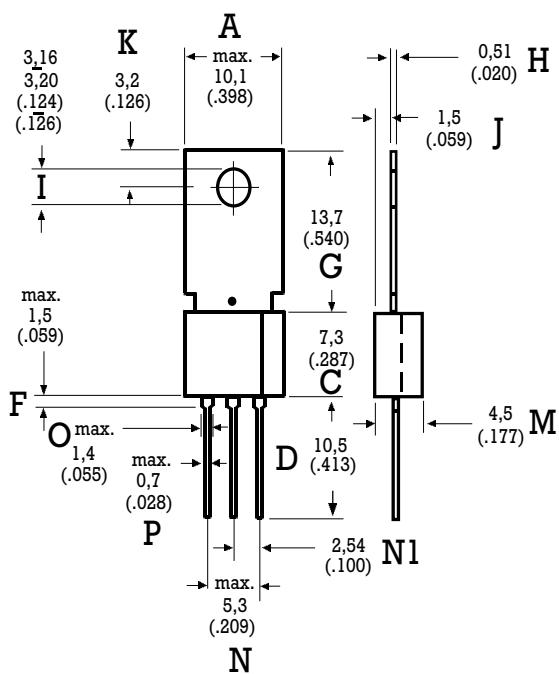
Fig. 9: On-state characteristics (maximum values).



PACKAGE MECHANICAL DATA

TO 202-1 TO 202-3

TO 202-1



TO 202-3

